Search Notes			

Application/Control No.	Applicant(s)/Pate Reexamination
10/620,376	HAYASHI ET A
Examiner	Art Unit

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/620,376	HAYASHI ET AL.	
Examiner	Art Unit	
Dah-Wei D. Yuan	1745	

SEARCHED			
Class	Subclass	Date	Examiner
429	34	7/24/2006	DWY
429	35	7/24/2006	DWY
429	36	7/24/2006	DWY
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT	ES STRATEGY)
	DATE	EXMR
EAST	7/24/2006	DWY
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